

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10776789	BEDNASZ ET AL.
Examiner	Art Unit	
Pan, Yuwen	2618	

### SEARCHED

Class	Subclass	Date	Examiner
455	67.11, 67.14	1/16/08	YP
343	703, 702	1/16/08	YP

### SEARCH NOTES

Search Notes	Date	Examiner
EAST text search	1/16/08	YP

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner